

Recitation 11: Small Signal Model of MOSFET/MOSFET in Digital Circuits

Small Signal Models

On Tuesday we talked about *small signal models of MOSFETs*. Why do we need small signal modeling?

To linearize circuits. Linear circuits are much easier to work with: we can use Thevenin/Norton equivalent circuits, superposition, etc.

How to obtain a linearized circuit?

If we limit our signals to a relatively small amplitude, (this is in fact most often the case), the non-linear IV curves (as seen in 1 for example) can be considered piece-wise linear \implies small signal model.

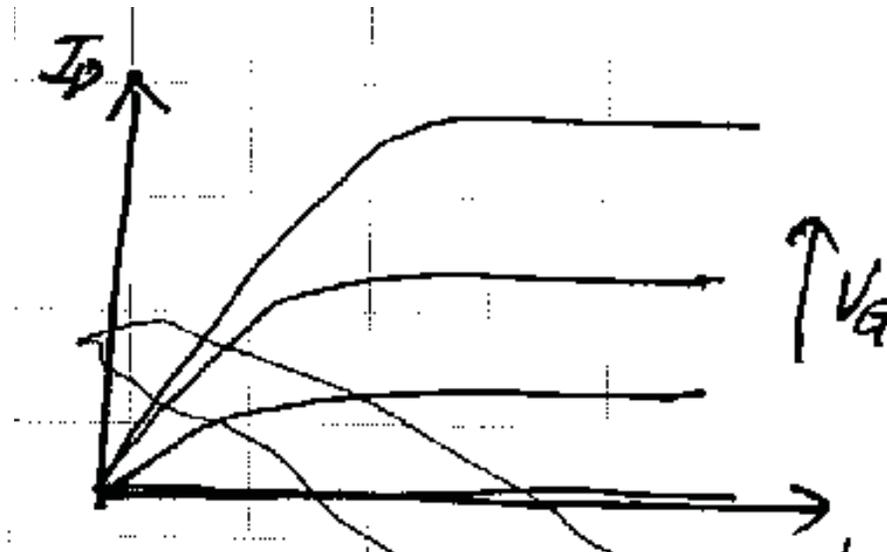


Figure 1: Non Linear IV Curves

A MOSFET is a 4-terminal device (NMOS as an example)

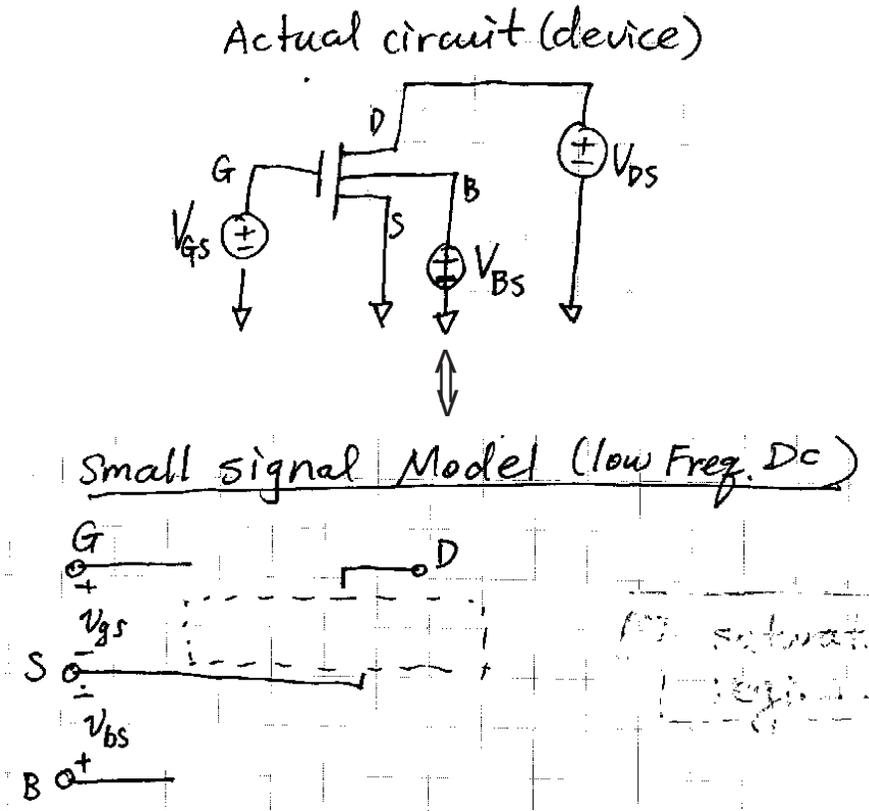


Figure 2: NMOS

- cut-off $i_d = 0$
- triode/linear

$$i_d = \frac{w}{L} \mu_n C_{ox} \left(V_{GS} - \frac{V_{DS}}{2} - V_T \right) \cdot V_{DS}$$

- Saturation

$$i_d = \frac{w}{2L} \mu_n C_{ox} (V_{GS} - V_T)^2 \cdot (1 + \lambda V_{DS})$$

In small signal modeling it is very important to differentiate:

i_D ← total signal ($i_D = I_D + i_d$)

I_D ← DC signal

i_d ← small signal

What Happens at Low Frequency?

To obtain a small signal equivalent circuit, we need to find an operation point first: $Q(V_{DS}, V_{GS}, V_{BS})$. (Q is a specific point on Fig. 1) thus I_D is also known.

Then, what is in between D & S in Figure ?? depends on:

$$\begin{aligned} i_d &= \left. \frac{\delta i_d}{\delta V_{GS}} \right|_Q \cdot V_{GS} + \left. \frac{\delta i_d}{\delta V_{DS}} \right|_Q \cdot V_{DS} + \left. \frac{\delta i_d}{\delta V_{BS}} \right|_Q \cdot V_{BS} \\ &= g_m \cdot V_{GS} + g_o \cdot V_{DS} + g_{MB} \cdot V_{BS} \quad \text{three conductances in parallel } (\because \text{they add up}) \end{aligned}$$

- g_m : trans-conductance (unit S)
- g_o : output conductance (unit S)
- g_{mb} : backgate transconductance (unit S)

On Tuesday, we derived the expression for g_m, g_o, g_{mb} in *saturation regime*

$$\begin{aligned} g_m &= \left. \frac{\delta i_d}{\delta V_{GS}} \right|_Q = \left. \frac{\delta \left[\frac{w}{2L} \mu_n C_{ox} (V_{GS} - V_T)^2 (1 + \lambda V_{DS}) \right]}{\delta V_{GS}} \right|_{Q(V_{GS}, V_{DS}, V_{BS})} \\ &= \frac{w}{2L} \mu_n C_{ox} (1 + \lambda V_{DS}) (V_{GS} - V_T) \cdot 2 \\ &\simeq \frac{w}{L} \mu_n C_{ox} (V_{GS} - V_T) = \sqrt{\frac{2w}{L} \mu_n C_{ox} I_D} \rightarrow g_m \propto \sqrt{\frac{w}{L} I_D} \\ g_o &= \left. \frac{\delta i_D}{\delta V_{DS}} \right|_Q = \frac{w}{2L} \mu_n C_{ox} (V_{GS} - V_T)^2 \cdot \lambda \simeq \lambda I_D \\ \gamma_o &= \frac{1}{g_o} = \frac{1}{\lambda I_D} \propto \frac{L}{I_D} \\ g_{mb} &= \left. \frac{\delta i_D}{\delta V_{BS}} \right|_Q = \frac{w}{2L} \mu_n C_{ox} (1 + \lambda V_{DS}) \cdot (-2)(V_{GS} - V_T) \cdot \left. \frac{\delta V_T}{\delta V_{BS}} \right|_Q \\ &\simeq \underbrace{\left(-\frac{w}{L} \mu_n C_{ox} (V_{GS} - V_T) \right)}_{g_m} \left. \frac{\delta V_T}{\delta V_{BS}} \right|_Q \\ &= +g_m \cdot \gamma \cdot \frac{1}{2\sqrt{-2\phi_p - V_{BS}}} \\ V_T &= V_{T_o} + \gamma(\sqrt{-2\phi_p - V_{BS}} - \sqrt{-2\phi_p}) \end{aligned}$$

Now what does the small signal circuit look like?

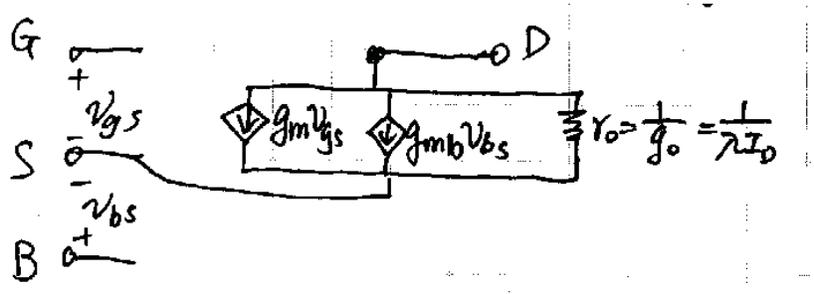


Figure 3: Low Frequency Small Signal Circuit. Two of them are voltage controlled current sources, one is a resistor. Why?

What Happens at High Frequency?

There are intrinsic or parasitic capacitances related to the MOSFET structure, as we know $Z_c = \frac{1}{j\omega C}$. At low frequency, Z_c is very large, can be approximated to open circuit, however at high frequency, Z_c is small enough we have to consider.

We have 4 terminals. Considering the possible combinations between them, we have:

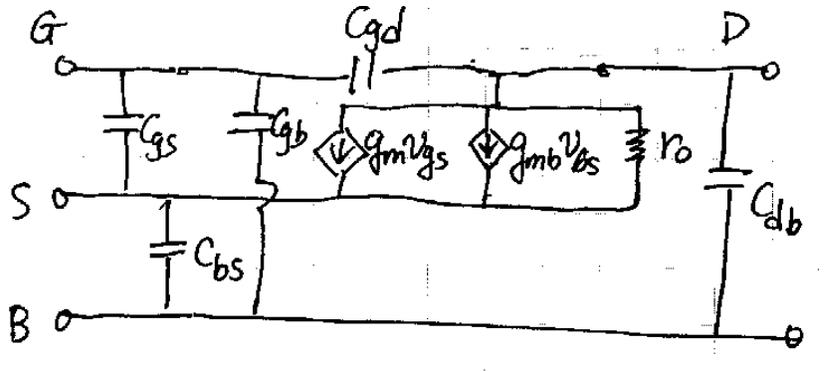


Figure 4: Between D & S, we have conduction channel, no capacitance between D & S

What are these capacitances (under saturation)?

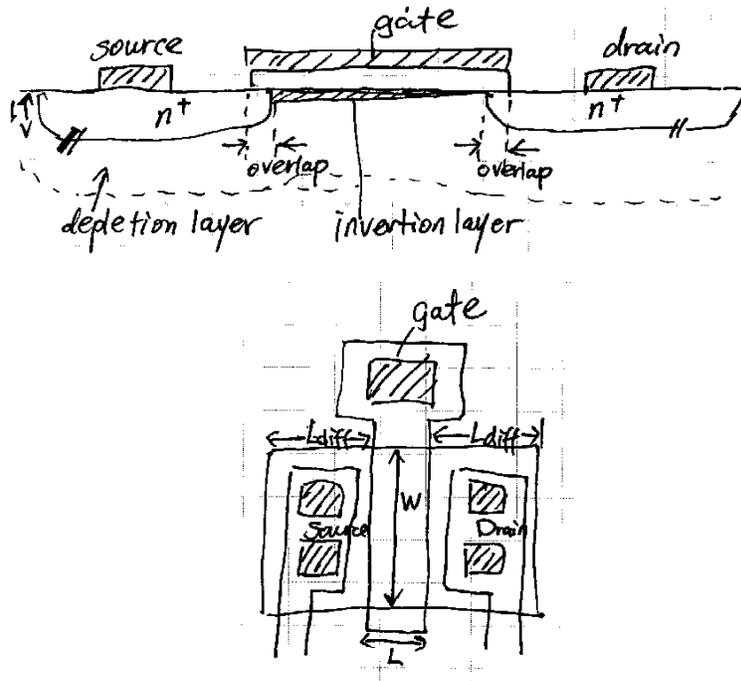


Figure 5: Capacitances (under saturation)

1. C_{gs} , two contributions, first is the MOS capacitor capacitance under inversion was C_{ox} before, but since under saturation regime, we have large V_{DS} , the inversion layer is non-uniform in charge density, need to do integration of q_G to consider this. We will skip the math here since it is derived in lecture already. The result is $wLC_{ox} \rightarrow \frac{2}{3}C_{ox} \cdot wL$. The other contribution is from the overlap between the source and gate C_{ov}

$$\therefore C_{GS} = \frac{2}{3}wL \cdot C_{ox} + w \cdot C_{ov} \quad C_{ov} \text{ unit is } F/cm$$

2. $C_{GD} = w \cdot C_{ov}$ L, L_{diff}, w , see Fig. 5 above
3. C_{BS} or C_{SB} = pn junction capacitance underneath the source area and side wall, is:

$$= w \cdot L_{diff} C_j^{(s)} + (2L_{diff} + w) \cdot C_{jsw}(s)$$

$$C_j^{(s)} = \sqrt{\frac{q\epsilon_s N_a}{2(\phi_B - V_{BS})}}$$

$$C_{jsw}(s) \text{ is usually given, should be } \sqrt{\frac{q\epsilon_s N_a}{2(\phi_B - V_{BS})}} \cdot d$$

4. C_{bd} or C_{db} = pn junction capacitance underneath the drain area and side wall, is:

$$= w \cdot L_{\text{diff}} \cdot C_j^{(D)} + (2L_{\text{diff}} + w) \cdot C_{j\text{sw}}^{(D)}$$

$$C_j^{(D)} = \sqrt{\frac{q\epsilon_s N_a}{2(\phi_B - V_{BD})}}$$

5. C_{gb} is due to the presence of inversion layer (screening) under inversion, the capacitance of C_{gb} can be ignored (it only present at cut off).

MOSFETS in Digital Circuits

Now we have both the low frequency and high frequency version of the small signal equivalent circuit. What has it to do with our MOSFET digital circuit discussion?

For digital circuits, there are two important aspects:

1. Noise Margin: larger noise margin \rightarrow higher noise immunity, better
2. Speed: the concept of “propagation delay”. We want circuit response to be fast, \Rightarrow low propagation delay

Now the question is, when we design a circuit, what parameters affect the noise margin and what affects the delay?

Noise Margin

Our inverter is shown below:

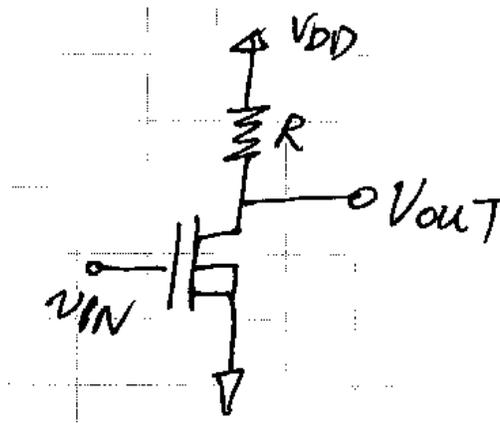
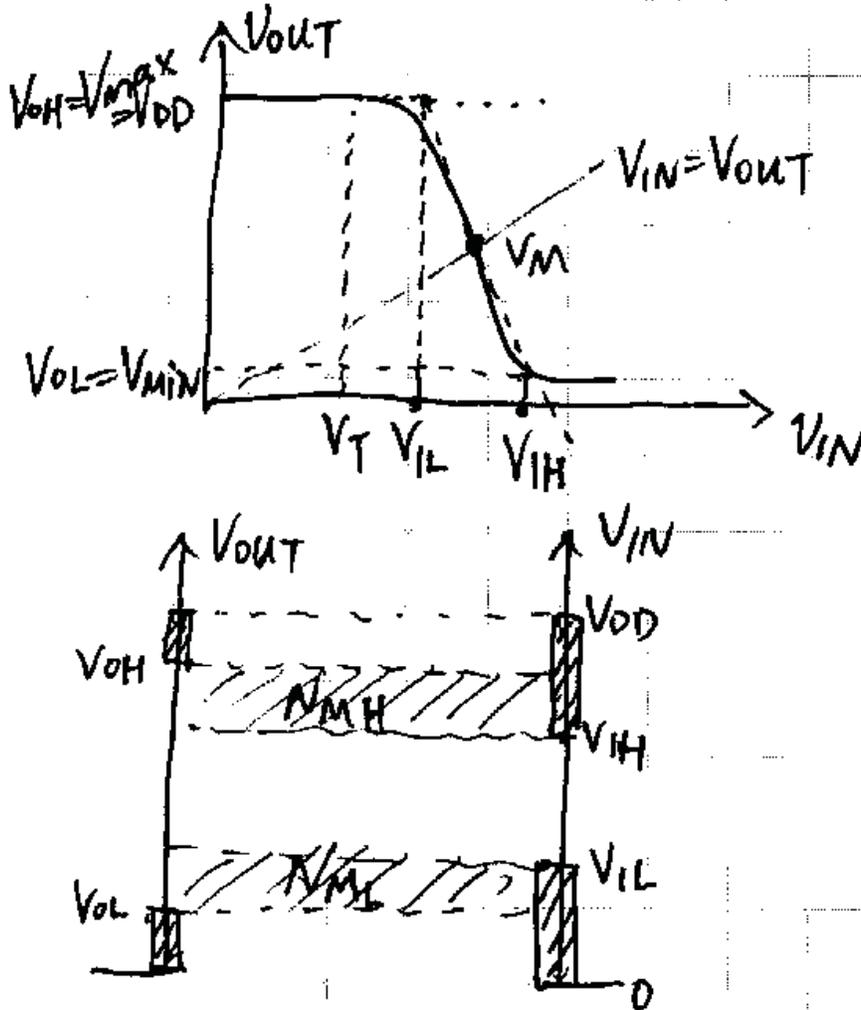


Figure 6: n-MOS inverter

$$N_{MH} = V_{OH} - V_{IH}$$

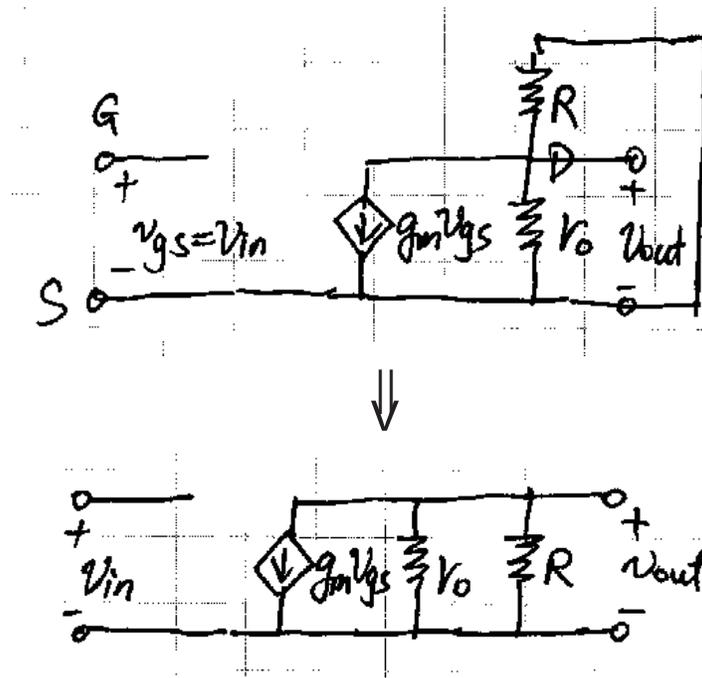
$$N_{ML} = V_{IL} - V_{OL}$$

In order to have a high noise margin, we want high slope at $V_m \implies$ high gain A_v at V_m .



Gain

How to find gain at V_m ? Use a small signal circuit:



$$A_v = \frac{V_{out}}{V_{in}} = -g_m(r_o \parallel R) \simeq -g_m R$$

The larger the R the bigger the noise margin. However, as we will see later, the larger R the slower the circuit. There is a tradeoff since capacitances in the circuit add delay.

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6.012 Microelectronic Devices and Circuits
Spring 2009

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